Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/659,101	CHAN ET AL.
Examiner	Art Unit
Randall Chin	1744

SEARCHED					
Class	Subclass	Date	Examiner		
15	143.1	1	J		
15	167.1	8/1/2005	RC		
15	22.1				
UPPATE	22.1 DSEMEN	3/5/06	pe		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
Inventor name search	8/1/2005	RC
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